

Form PTO-1449
(Rev. 8-83)

Department of Commerce
Patent and Trademark Office

Atty. Docket No.
0756-1299

Serial No. (TO BE
ASSIGNED)
Based on S.N. ~~00-709,220~~

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant
Hongyong ZHANG et al.

Filing Date
June 5, 1995

Group ~~2508~~ 2823

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

OTHER DOCUMENTS (Including Author, Title, Date)	
K.N.	<p>U C. Hayzelden et al., "In Situ Transmission Electron Microscopy Studies of Silicide-Mediated Crystallization of Amorphous Silicon" (2 pages) <u>Appl. Phys. Lett.</u> <u>60, 2 (1992) 225</u></p>
K.N.	<p>U A.V. Dvurechenskii et al., "Transport Phenomena in Amorphous Silicon Doped by Ion Implantation of 3d Metals", <u>Andreevskian Laureatev PROSpekt</u> <u>21, 520000 Novosibirsk 90, USSR</u> pp. 535-540. <u>PHYS. STAT. SOL. A95 (1986) 635</u></p>
K.N.	<p>U T. Hempel et al., "Needle-Like Crystallization of Ni Doped Amorphous Silicon Thin Films", <u>Solid State Communications</u>, Vol. 85, No. 11, pp. 921-924, 1993.</p>

Examiner

Date Considered

Examiner CRADONSKY Date Considered 11/1/20

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sheet 1 of 1

Submitted with IDS of May 17, 1999

Form PTO-1449
(Rev. 8-83)MAY 21 1999 U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No. 0756-1641

Serial No. 08/811,742

INFORMATION DISCLOSURE STATEMENT

Applicant: Hongyong ZHANG et al.

Filing Date: March 6, 1997

Group: 2823

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SAH	5,075,259	12/24/91	Moran	—	—	—
SAH	3,783,049	01/01/74	Sandera	—	—	—
SAH	5,300,187	04/05/94	Lesk et al	—	—	—
SAH	5,244,819	09/14/93	Yue	—	—	—
SAH	5,298,075	03/29/94	Legendijk et al	—	—	—
SAH	5,225,355	07/06/93	Sugino et al	—	—	—
SAH	4,231,809	11/04/80	Schmidt	—	—	—
SAH	RE 28,386	04/08/75	Heiman et al	—	—	—
SAH	RE 28,385	04/08/75	Mayer	—	—	—
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SAH	Wolf, "Silicon Processing for the VLSI ERA Volume 2: Process Integration", Lattice Press, June 1990, p. 144-146
SAH	Fortuna et al., "In Situ Study of Ion Beam Induced Si Crystallization from a Silicide Interface", Applied Surface Science, Vol. 73, 1993, pp. 264-267
SAH	Lee et al., "Pd Induced Lateral Crystallization of Amorphous Si Thin Films", Appl. Phys. Lett., Vol. 66, No. 13, March 27, 1995, pp. 1671-1673
SAH	Green et al., "Method to Purify Semiconductor Wafers", IBM Technical Disclosure Bulletin, Vol. 16, No. 5, October 1973, pp. 1612-1613
SAH	Lee et al., "Low Temperature Poly-Si TFT Fabrication by Nickel-Induced Lateral Crystallization of Amorphous Silicon Films", Japan Society of Applied Physics AM-LCD 95 Digest of Technical Papers, Osaka, Japan, August 24-25, 1995, pp. 113-116
SAH	Gong et al., "Thermodynamic Investigations of Solid-State Si-Metal Interactions. II. General Analysis of Si-Metal Binary Systems", J. Appl. Phys., Vol. 68, No. 9, November 1, 1990, pp. 4542-4549
SAH	Kakkad et al., "Crystallized Si Films by Low-Temperature Rapid Thermal Annealing of Amorphous Silicon", J. Appl. Phys., Vol. 65, No. 5, March 1, 1990, pp. 2069-2072
SAH	Liu et al., "Polycrystalline Silicon Thin Film Transistors on Corning 7059 Glass Substrates using Short Time, low-Temperature Processing", Appl. Phys. Lett., Vol. 62, No. 20, May 17, 1993, pp. 2554-2556
SAH	Liu et al., "Selective Area Crystallization of Amorphous Silicon Films by Low-Temperature Rapid Thermal Annealing", Appl. Phys. Lett., Vol. 55, No. 7, August 14, 1989, pp. 660-662
SAH	Caune et al., "Combined CW Laser and Furnace Annealing of Amorphous Si and Ge in Contact with Some Metals", Applied Surface Science, Vol. 36, 1989, pp. 567-604

Examiner

Date Considered

7/28/99

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Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known

Application Number	08/811,742
Filing Date	March 6, 1997
First Named Inventor	Hongyong Zhang et al.
Group Art Unit	2823
Examiner Name	Scott A. Brainton <i>Khiem D. Nguyen</i>
Attorney Docket Number	740756-1641

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Examiner Initials [*]	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ³ (if known)			
<i>K.N.</i>		5,814,540		Takemura et al.	09-29-1998	
<i>K.N.</i>		5,077,233		Mukai	12-31-1991	

FOREIGN PATENT DOCUMENTS

Examiner Initials [*]	Cite No. ¹	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Office ²	Number ⁴ (if known)				
<i>K.N.</i>		EP 0 178 447	B1	Mukai	04-23-1986		Full

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

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Examiner Signature	<i>Khiem D. Nguyen</i>	Date Considered	11/11/02
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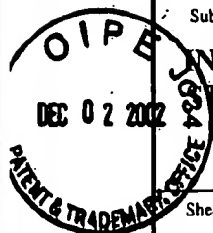
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	08/811,742
		Filing Date	March 6, 1997
		First Named Inventor	Hongyong ZHANG et al.
		Art Unit	2823
		Examiner Name	Khiem D. Nguyen
		Attorney Docket Number	740756-1641
Sheet		of	

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		Country Code ³	Number ⁴ (if known)				
K.N.		JP	04-022120	01/27/1992	Masabumi Kunii		AB

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Examiner Signature	Khiem D. Nguyen	Date Considered	05/15/03
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		Examiner Name	Khiem D. Nguyen
Sheet 1 of 1	Attorney Docket Number	740756-1641	

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		Number - Kind Code ³ (if known)			
K.N.		US-6.486,497	11-26-2002	Misawa et al.	
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		Country Code ⁵ Number ⁶ Kind Code ³ (if known)				
K.N.		EP 0 342 925 A2	11-23-1989	Misawa et al.		Full

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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K.N.		CHINESE OFFICE ACTION DATED SEPTEMBER 5, 2003	

Examiner Signature	<i>Khiem D. Nguyen</i>	Date Considered	04/26/04
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